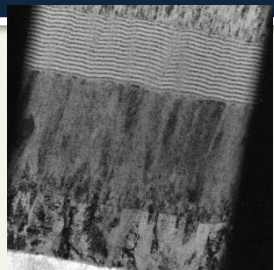
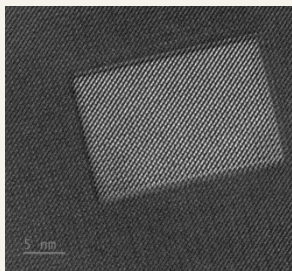


穿透式電子顯微鏡(TEM)特點

多層狀結構的厚度量測

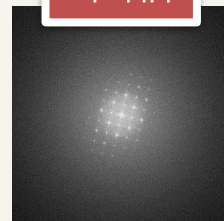


達到原子等級解析度

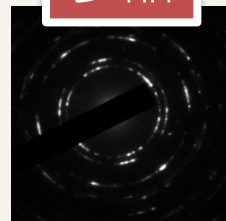


判斷材料晶體結構

單晶

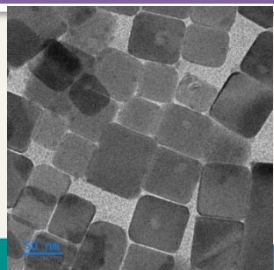


多晶



晶柱尺寸量測和分佈(暗場像)

奈米顆粒量測和分佈

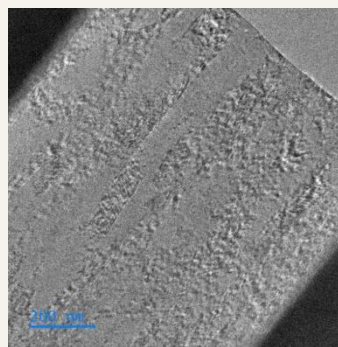
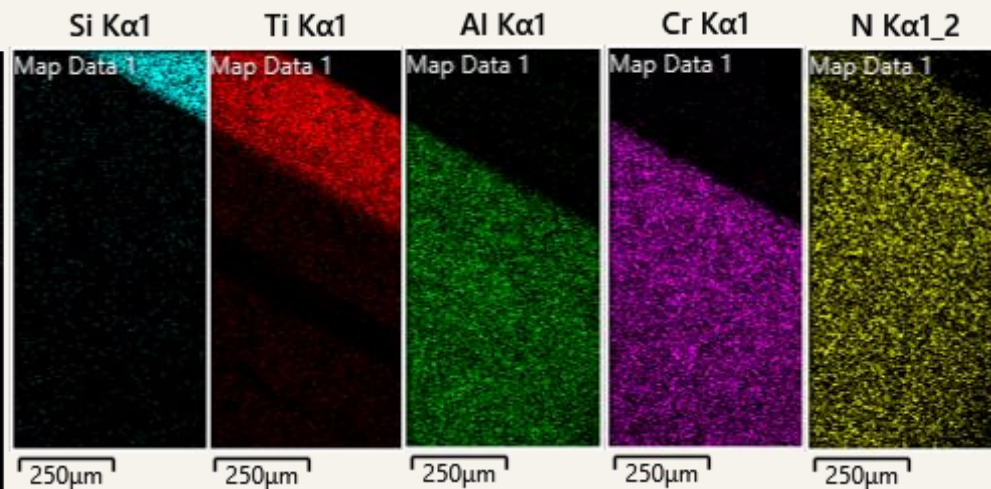
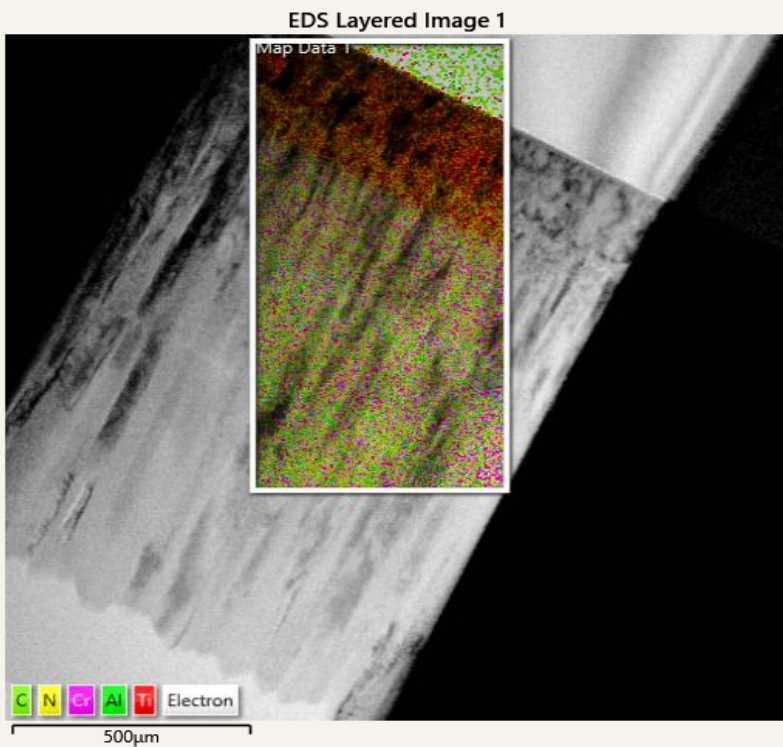


材料成分分析(STEM/EDS)

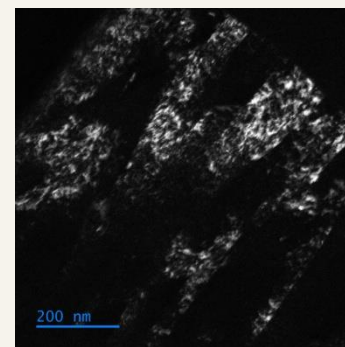


STEM檢測項目-Mapping、明場相、暗場相

STEM表面元素分佈分析



明場相



暗場相

